

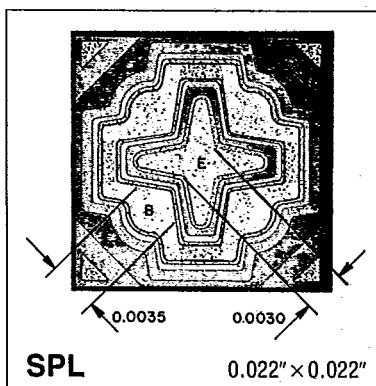
PROCESS SPL

Process SPL NPN Small-Signal Transistor

Process SPL is a double-diffused NPN silicon epitaxial transistor. It is designed to be used in general-purpose amplifier and medium-power switching applications.

ABSOLUTE MAXIMUM RATINGS

Collector Current, I_C 500 mA
 Operating Junction Temperature, T_J +150°C
 Storage Temperature Range, T_S -55°C to +150°C



SPL 0.022" x 0.022"
 ALTERNATE PROCESS: DCA

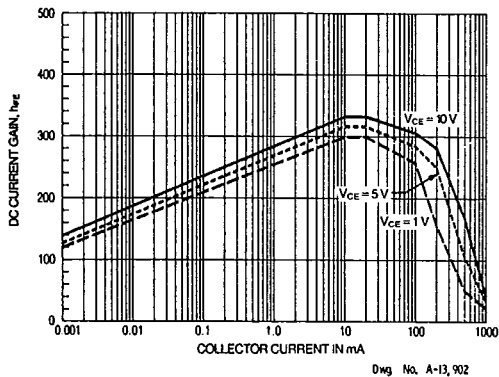
ELECTRICAL CHARACTERISTICS at $T_A = +25^\circ\text{C}$

Characteristic	Symbol	Test Conditions	Limits			Units
			Min.	Typ.	Max.	
Collector-Emitter Breakdown Voltage	$V_{(BR)CEO}$	$I_C = 10\text{ mA}$	30	50	—	V
Emitter-Base Breakdown Voltage	$V_{(BR)EBO}$	$I_E = 10\ \mu\text{A}$	6.0	7.5	—	V
Collector-Base Breakdown Voltage	$V_{(BR)CBO}$	$I_C = 100\ \mu\text{A}$	60	110	—	V
Collector Cutoff Current	I_{CBO}	$V_{CB} = 50\text{ V}$	—	—	100	nA
Emitter Cutoff Current	I_{EBO}	$V_{EB} = 6.0\text{ V}$	—	—	100	nA
Static Forward Current Transfer Ratio	h_{FE}	$V_{CE} = 10\text{ V}, I_C = 0.1\text{ mA}$	—	260	—	—
		$V_{CE} = 10\text{ V}, I_C = 10\text{ mA}$	75	330	—	—
		$V_{CE} = 10\text{ V}, I_C = 100\text{ mA}$	100	300	—	—
Collector-Emitter Saturation Voltage	$V_{CE(sat)}$	$I_C = 100\text{ mA}, I_B = 10\text{ mA}$	—	0.1	0.25	V
		$I_C = 500\text{ mA}, I_B = 50\text{ mA}$	—	0.3	1.0	V
Base-Emitter Saturation Voltage	$V_{BE(sat)}$	$I_C = 500\text{ mA}, I_B = 50\text{ mA}$	—	1.1	2.0	V
Gain-Bandwidth Product	f_T	$V_{CE} = 10\text{ V}, I_C = 20\text{ mA}$	250	400	—	MHz
Output Capacitance	C_{cb}	$V_{CB} = 10\text{ V}, f = 1.0\text{ MHz}$	—	4.0	8.0	pF
Input Capacitance	C_{eb}	$V_{EB} = 0.5\text{ V}, f = 1.0\text{ MHz}$	—	17	25	pF
Delay Time*	t_d	$V_{CC} = 30\text{ V}, I_C = 150\text{ mA}, I_B = 15\text{ mA}$	—	8.0	10	ns
Rise Time*	t_r		—	15	25	ns
Storage Time*	t_s	$V_{CC} = 30\text{ V}, I_C = 150\text{ mA}, I_{B1} = I_{B2} = 15\text{ mA}$	—	160	225	ns
Fall Time*	t_f		—	40	60	ns

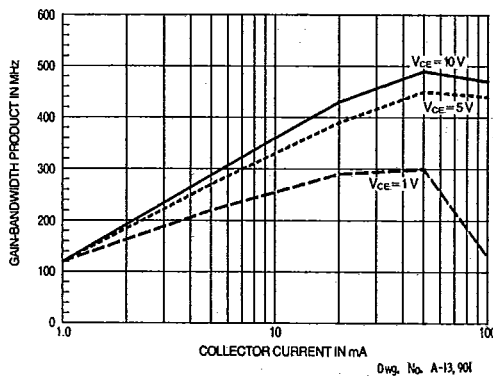
*Switching speeds measured at 2N2222A test conditions.

Typical Characteristics
at $T_A = +25^\circ\text{C}$

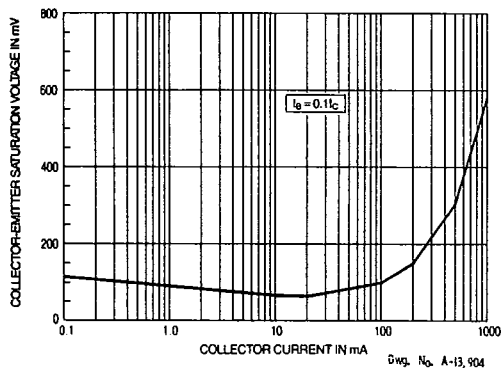
h_{FE} AS A FUNCTION
OF COLLECTOR CURRENT



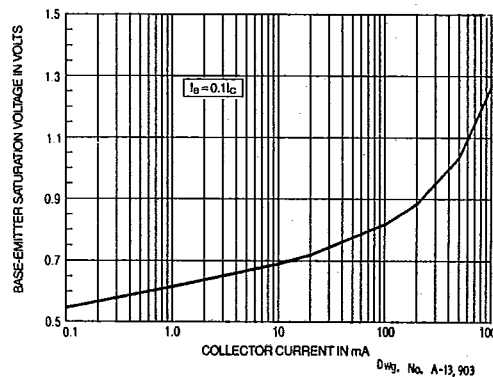
f_T AS A FUNCTION
OF COLLECTOR CURRENT



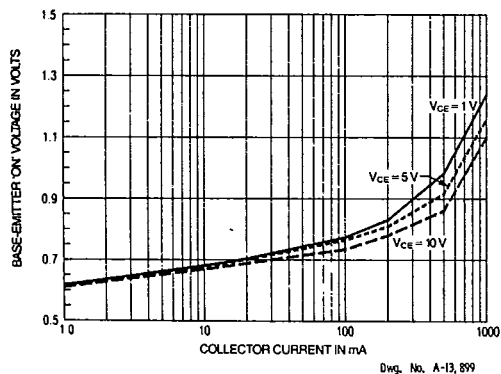
$V_{CE(sat)}$ AS A FUNCTION
OF COLLECTOR CURRENT



$V_{BE(sat)}$ AS A FUNCTION
OF COLLECTOR CURRENT



$V_{BE(on)}$ AS A FUNCTION
OF COLLECTOR CURRENT



JUNCTION CAPACITANCE
AS A FUNCTION OF REVERSE BIAS

